



Description

JMT N-channel Enhancement Mode Power MOSFET

Features

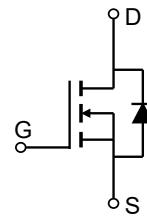
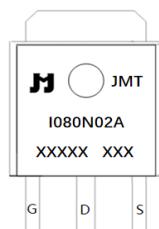
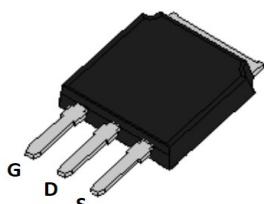
- 20V, 50A
- $R_{DS(ON)} < 7.5\text{m}\Omega$ @ $V_{GS} = 4.5\text{V}$
- $R_{DS(ON)} < 10.1\text{m}\Omega$ @ $V_{GS} = 2.5\text{V}$
- Advanced Trench Technology
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- Lead Free

Applications

- Load Switch
- PWM Application
- Power Management



100% UIS TESTED!
100% ΔV_{ds} TESTED!



TO-251-3L Top View

Marking and Pin Assignment

Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Outline	Package	TUBE (pcs)	Inner Box (pcs)	Per Carton (pcs)
JMTI080N02A	JMTI080N02A	TUBE	TO-251-3L	75	4950	29700

Absolute Maximum Ratings (@ $T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Value		Units
V_{DS}	Drain-to-Source Voltage		20		V
V_{GS}	Gate-to-Source Voltage		± 12		V
I_D	Continuous Drain Current	$T_C = 25^\circ\text{C}$	50		A
		$T_C = 100^\circ\text{C}$	32		
I_{DM}	Pulsed Drain Current ⁽¹⁾		200		A
E_{AS}	Single Pulsed Avalanche Energy ⁽²⁾		49		mJ
P_D	Power Dissipation	$T_C = 25^\circ\text{C}$	31		W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾		32		$^\circ\text{C}/\text{W}$
$R_{\theta JC}$	Thermal Resistance, Junction to Case		4		
T_J, T_{STG}	Junction & Storage Temperature Range		-55 to 150		$^\circ\text{C}$

**Electrical Characteristics** ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	20	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}$	-	-	1.0	μA
I_{GSS}	Gate-Body Leakage Current	$V_{DS} = 0\text{V}, V_{GS} = \pm 12\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.5	0.75	1.0	V
$R_{\text{DS(ON)}}$	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 4.5\text{V}, I_D = 25\text{A}$	-	5.8	7.5	$\text{m}\Omega$
		$V_{GS} = 2.5\text{V}, I_D = 10\text{A}$	-	7.8	10.1	$\text{m}\Omega$
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{GS} = 0\text{V}, V_{DS} = 10\text{V}, f = 1\text{MHz}$	-	1613	-	pF
C_{oss}	Output Capacitance		-	228	-	pF
C_{rss}	Reverse Transfer Capacitance		-	200	-	pF
Q_g	Total Gate Charge	$V_{GS} = 0 \text{ to } 4.5\text{V}$ $V_{DD} = 10\text{V}, I_D = 25\text{A}$	-	18	-	nC
Q_{gs}	Gate Source Charge		-	3.5	-	nC
Q_{gd}	Gate Drain("Miller") Charge		-	5.5	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{GS} = 4.5\text{V}, V_{DD} = 10\text{V}$ $I_D = 25\text{A}, R_{\text{GEN}} = 3\Omega$	-	9	-	ns
t_r	Turn-On Rise Time		-	19	-	ns
$t_{d(off)}$	Turn-Off Delay Time		-	38	-	ns
t_f	Turn-Off Fall Time		-	24	-	ns
Drain-Source Diode Characteristics and Max Ratings						
I_S	Maximum Continuous Drain to Source Diode Forward Current	-	-	50	A	
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	200	A	
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = 30\text{A}$	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	$I_F = 25\text{A}, di/dt = 100\text{A/us}$	-	7.5	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	1.6	-	nC

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

2. E_{AS} condition: Starting $T_J = 25^\circ\text{C}$, $V_{DD} = 10\text{V}$, $V_G = 10\text{V}$, $R_G = 25\text{ohm}$, $L = 0.5\text{mH}$, $I_{AS} = 14\text{A}$ 3. $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB4. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$.

Typical Performance Characteristics

Figure 1: Output Characteristics

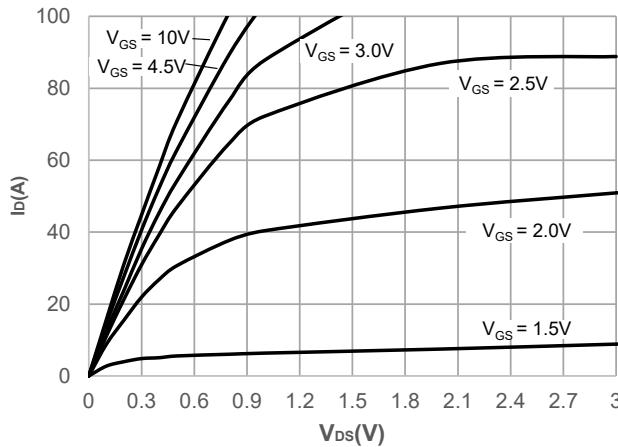


Figure 3: On-resistance vs. Drain Current

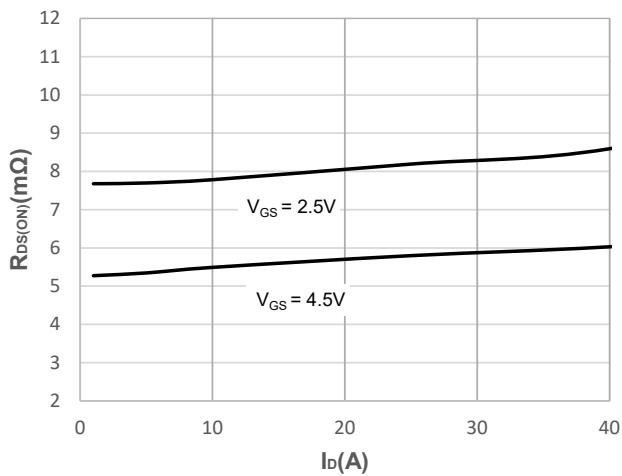


Figure 5: Gate Charge Characteristics

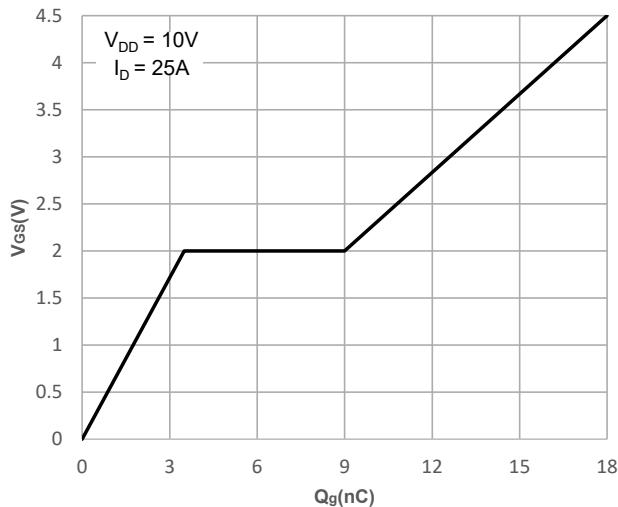


Figure 2: Typical Transfer Characteristics

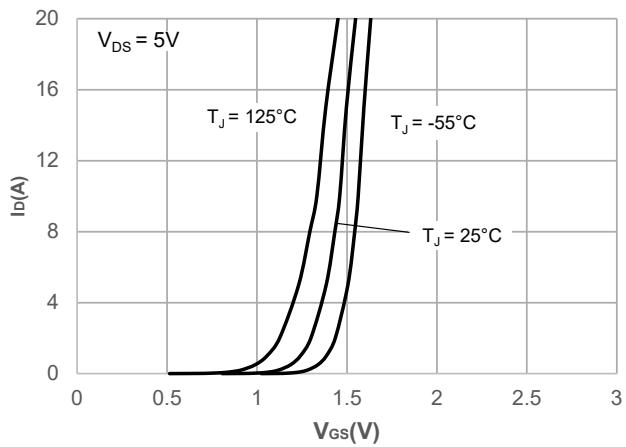


Figure 4: Body Diode Characteristics

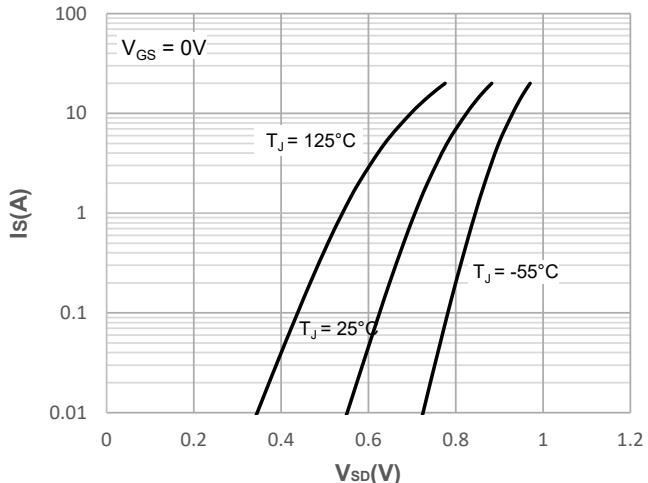
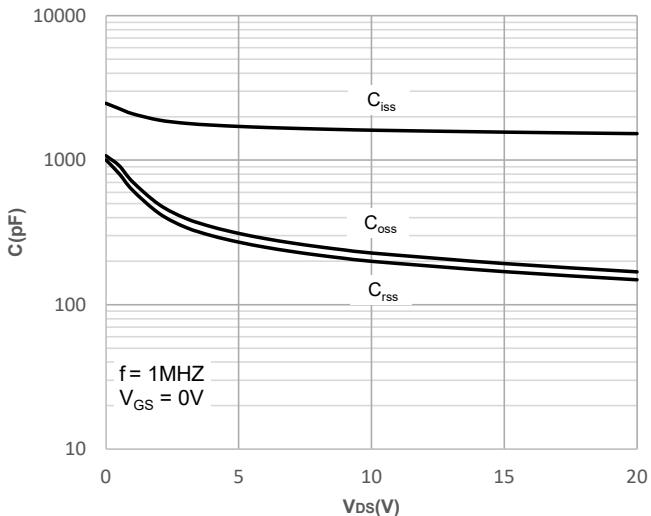


Figure 6: Capacitance Characteristics



Typical Performance Characteristics

Figure 7: Normalized Breakdown voltage vs. Junction Temperature

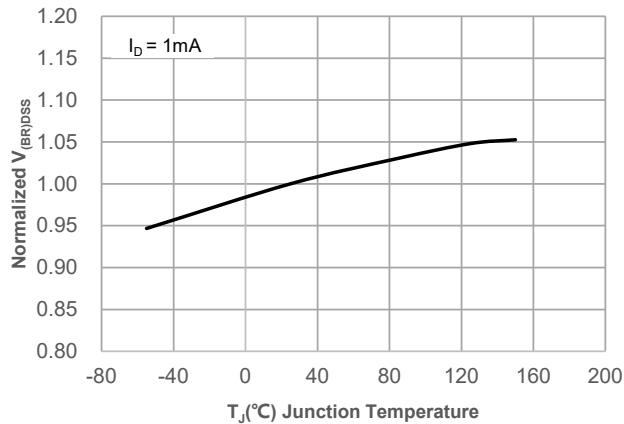


Figure 8: Normalized on Resistance vs. Junction Temperature

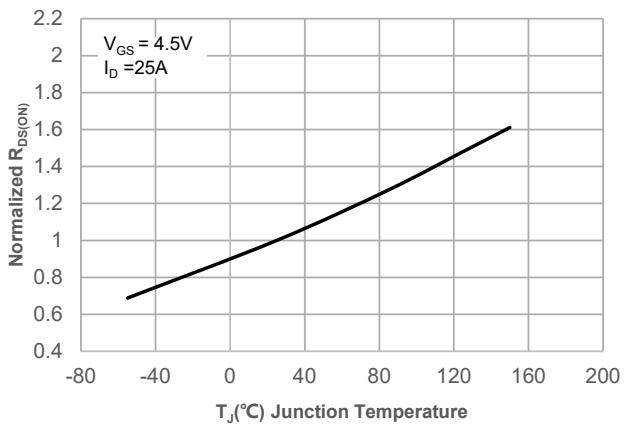


Figure 9: Maximum Safe Operating Area

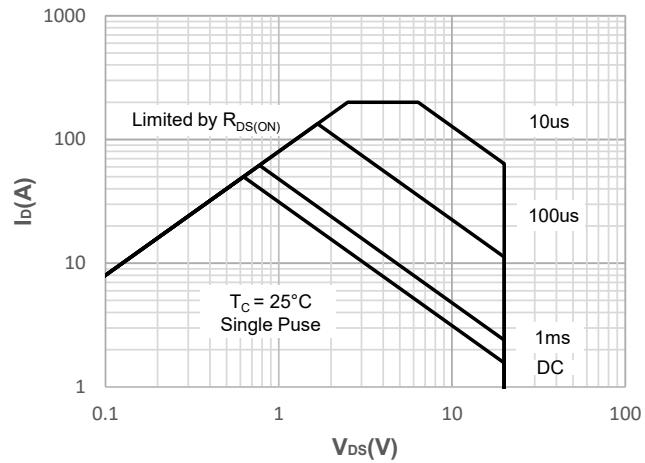


Figure 10: Maximum Continuous Drian Current vs. Case Temperature

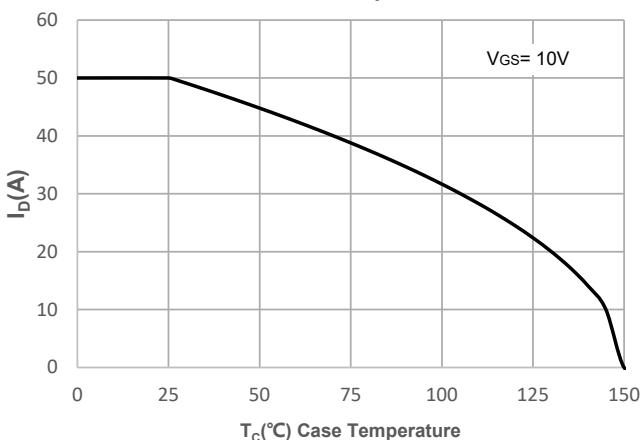


Figure 11: Normalized Maximum Transient Thermal Impedance

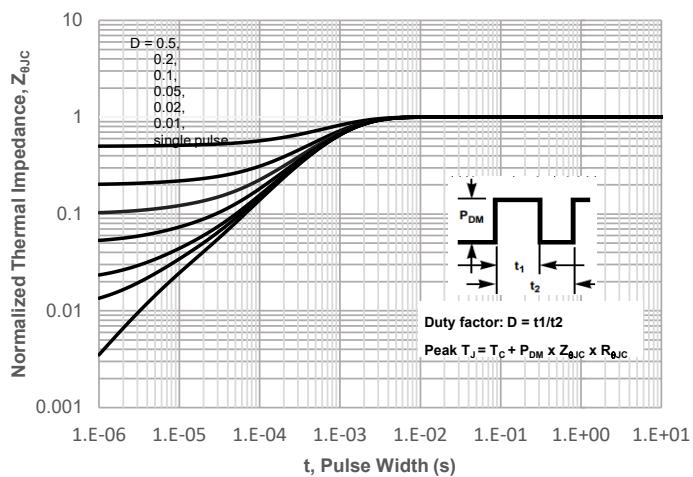
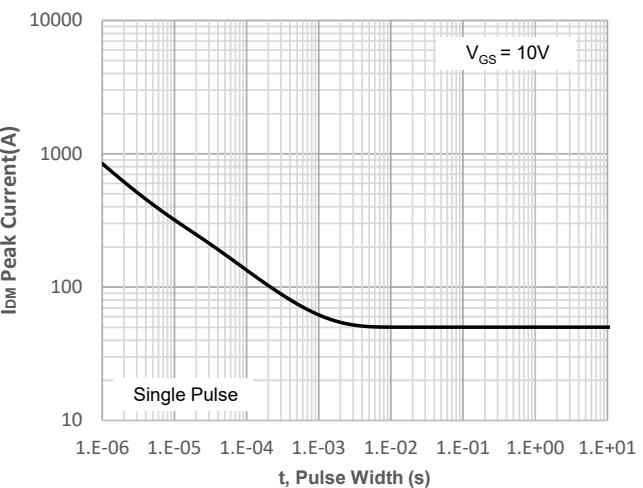


Figure 12: Peak Current Capacity



Test Circuit

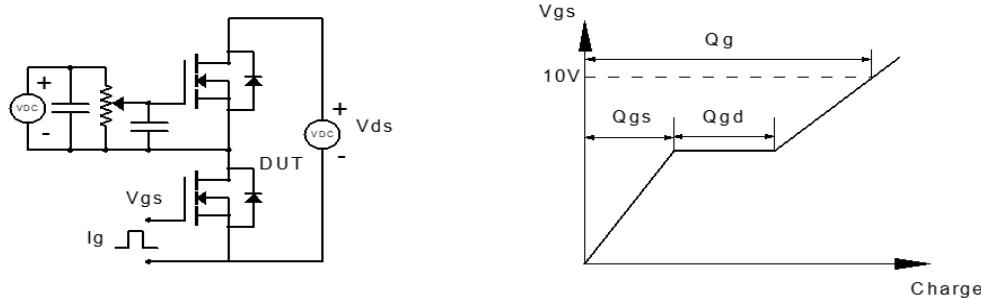


Figure 1: Gate Charge Test Circuit & Waveform

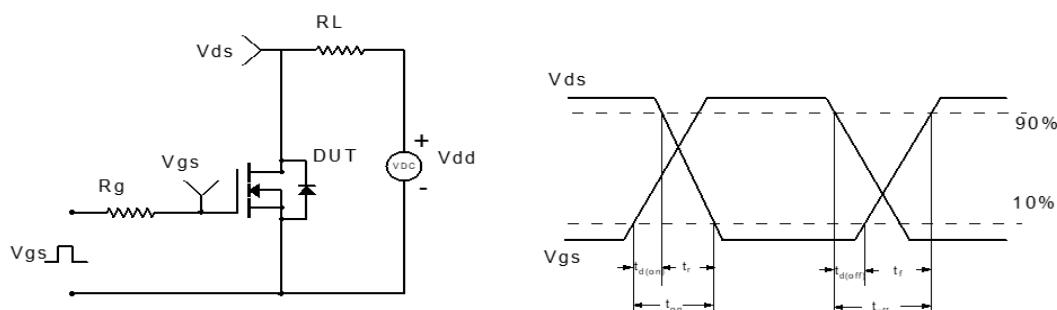


Figure 2: Resistive Switching Test Circuit & Waveform

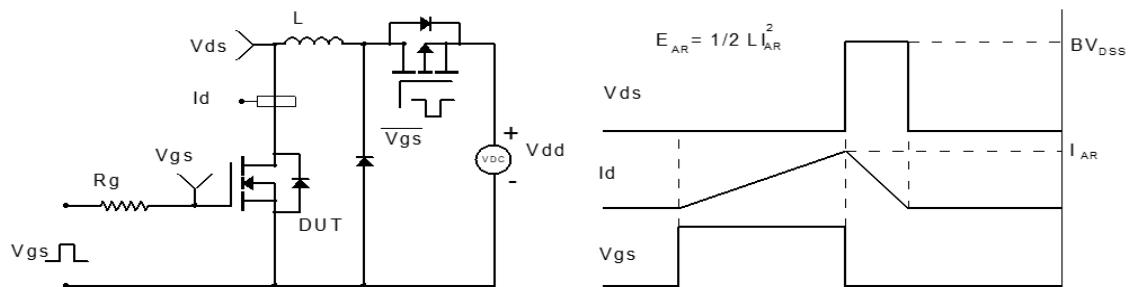


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

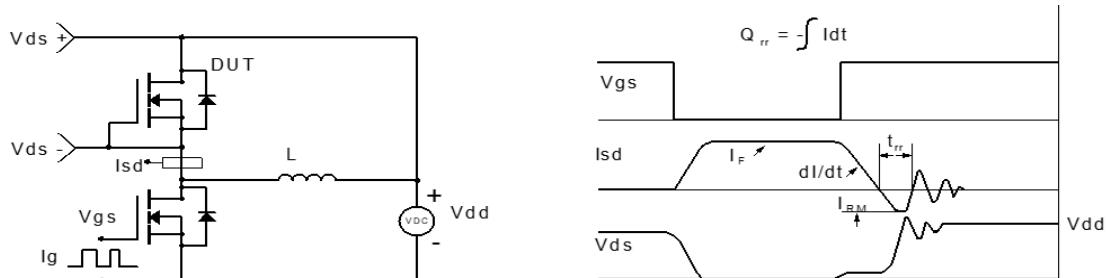
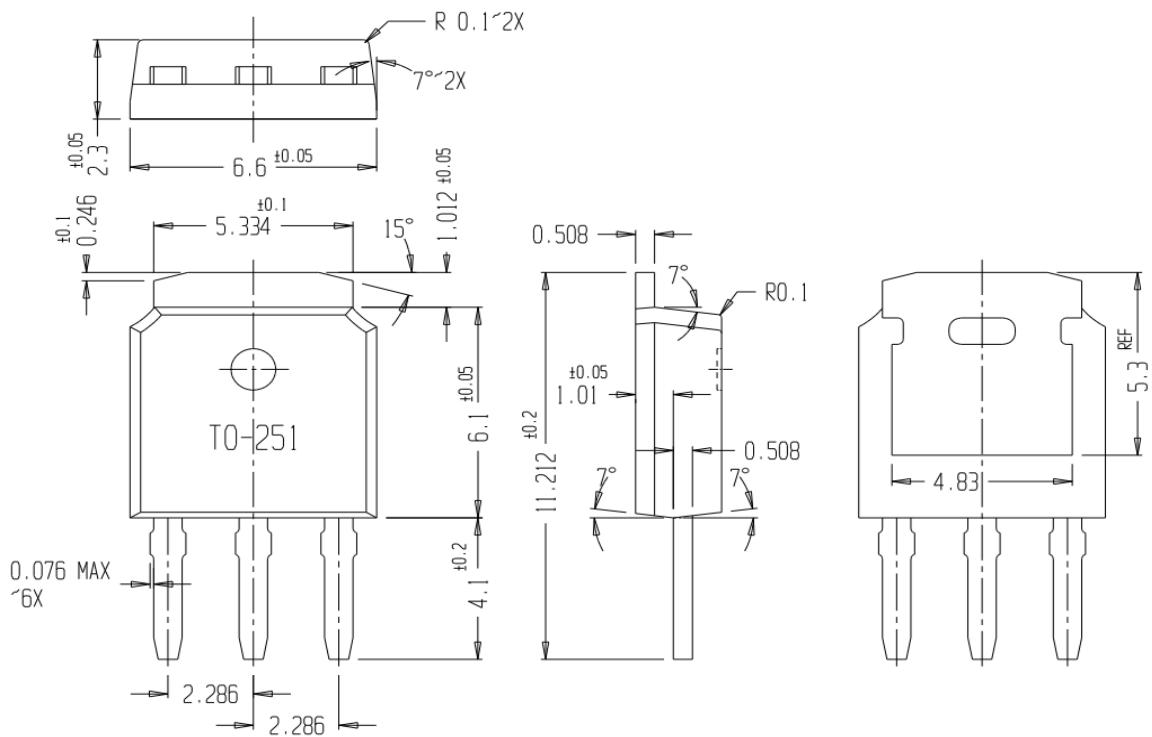


Figure 4: Diode Recovery Test Circuit & Waveform

Package Mechanical Data(TO-251-3L)



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